

Notice of References Cited	Application/Control No. 10/580,571		Applicant(s)/Patent Under Reexamination HARTIKAINEN ET AL.	
	Examiner TAN TRINH		Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0150228	10-2002	Umeda et al.	379/220.01
*	B	US-2004/0185885	09-2004	Kock, Martijn Willem Maria	455/466
*	C	US-2005/0065801	03-2005	Poikselka et al.	705/001
*	D	US-2003/0055949	03-2003	Coulombe et al.	709/224
*	E	US-2001/0031626	10-2001	Lindskog et al.	455/67.3
*	F	US-6,108,540	08-2000	Sonti et al.	455/433
*	G	US-2001/0051997	12-2001	Oku, Kazuho	709/217
*	H	US-6,944,169	09-2005	Yoshizawa et al.	370/410
*	I	US-5,086,452	02-1992	Ito et al.	455/561
*	J	US-7,142,847	11-2006	Umeda et al.	455/418
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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